

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination TO ET AL.	
		Examiner Hai C. Pham	Art Unit 2861	Page 1 of 1

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*	A	US-6,938,969	09-2005	Shibasaki, Souhei	347/12
	B	US-			
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	I	US-			
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	K	US-			
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	M	US-			

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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